



# Summary of Express Line TEC Module Results with ARC

III. Physikalisches Institut B

RWTH Aachen

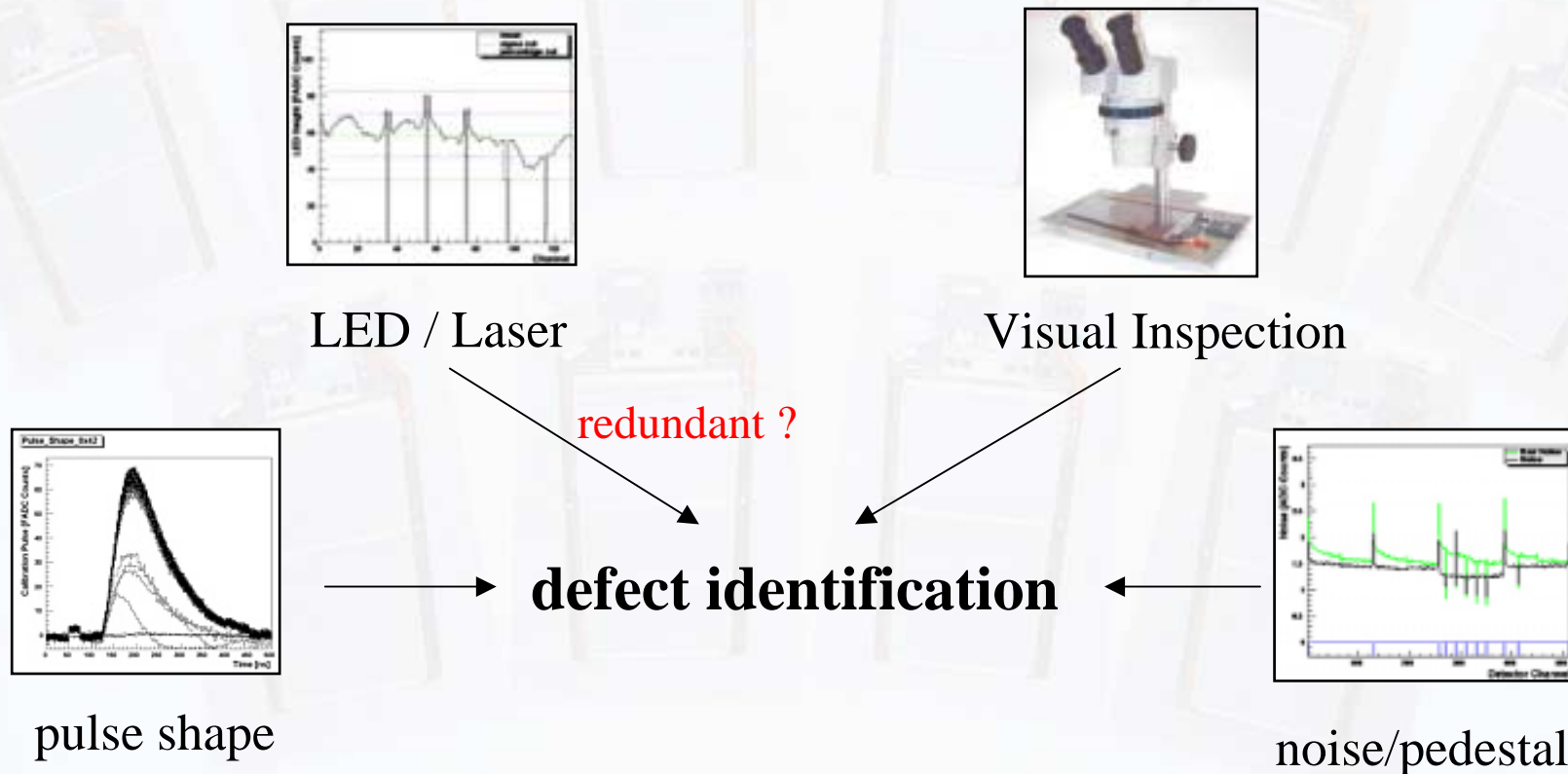
M. Axer, T. Franke, S. Kasselmann,  
J. Olzem (Aachen I B)



# Overview

- Characterization of typical module defects
- Tabularly summary of module test results
- Measurements with a cosmic test station
- What we have learned...
- Outlook

- Typical module defects: **open bonds, shorts, pinholes**. Other ones ?
- Each defect has its **characteristic symptoms** in different tests:



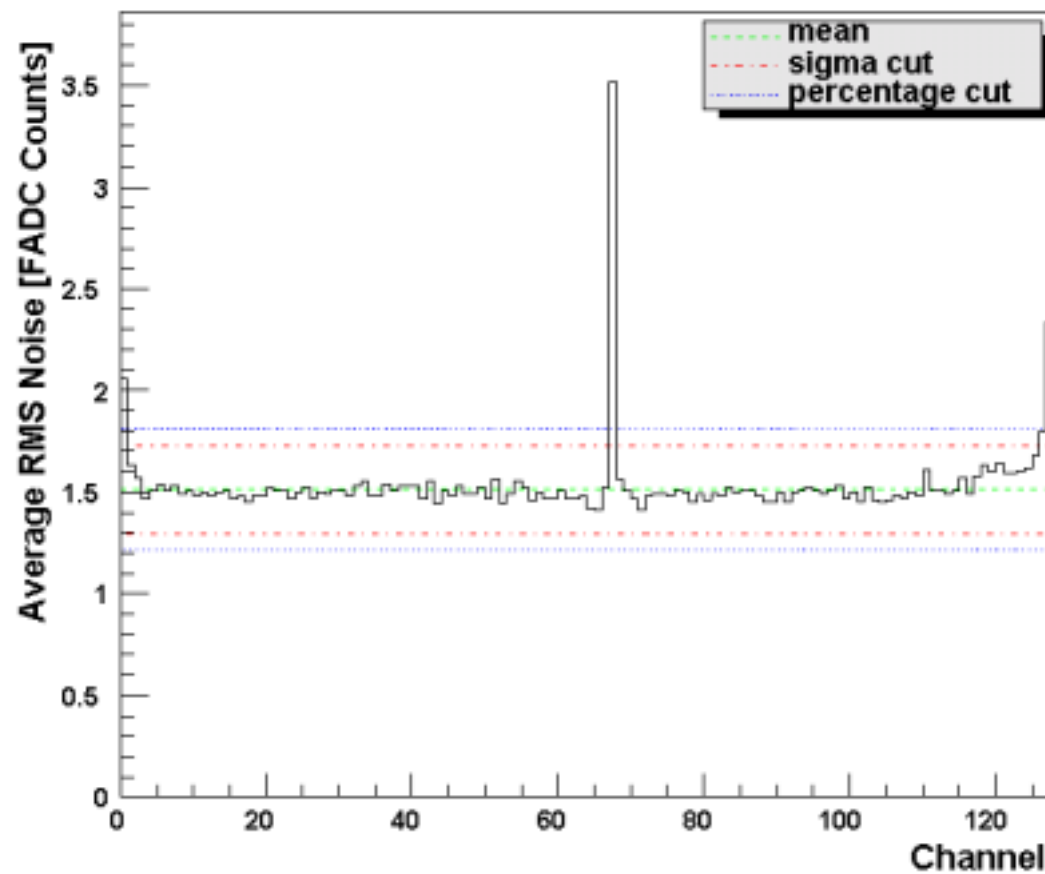


# Open Bonds



# Open Bonds I

- Most common defect and easy to detect.
- Noise: Conspicuously higher noise:



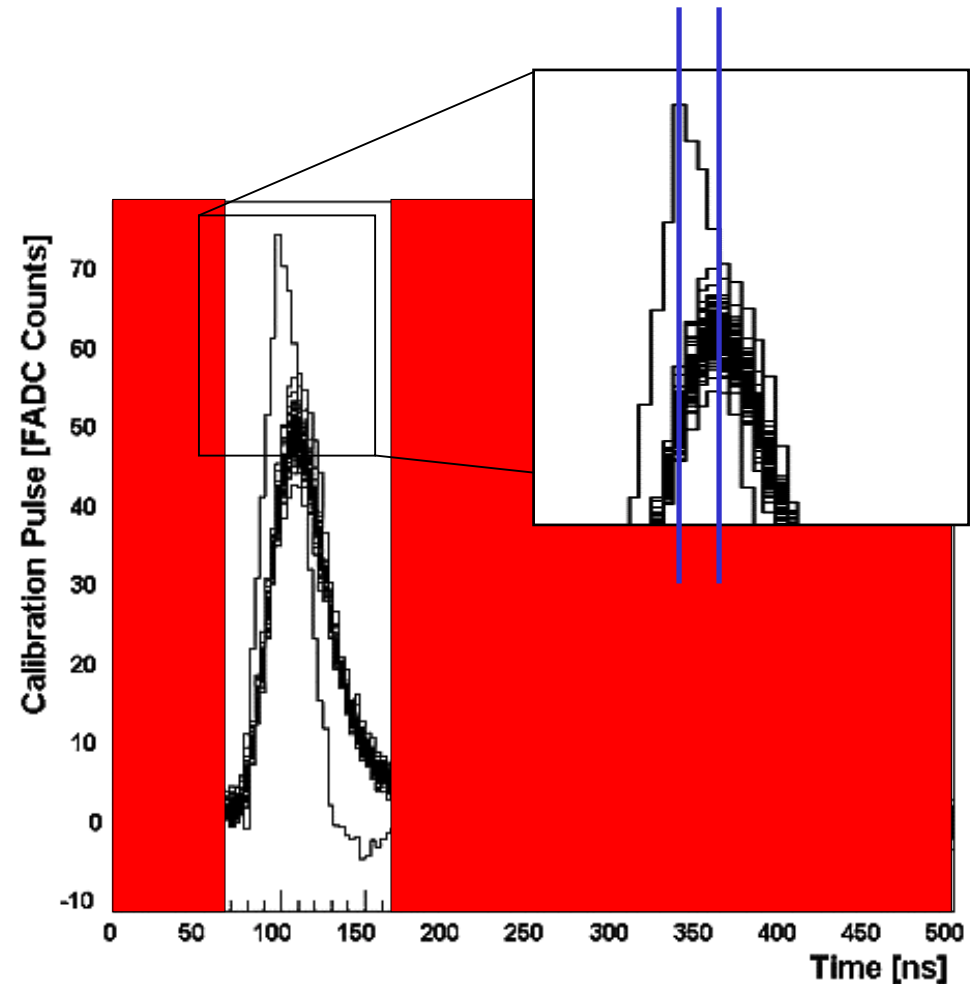
- Pulse Shape: Obviously different response to calibration pulse

- Higher maximum
- Faster rise time

- Is it sufficient to measure at the expected maximum only ?

No! The maximum is shifted (ca. 10 ns)

➔ Taking a 100 ns scan around the maximum (dec) should be sufficient!





# Open Bonds II

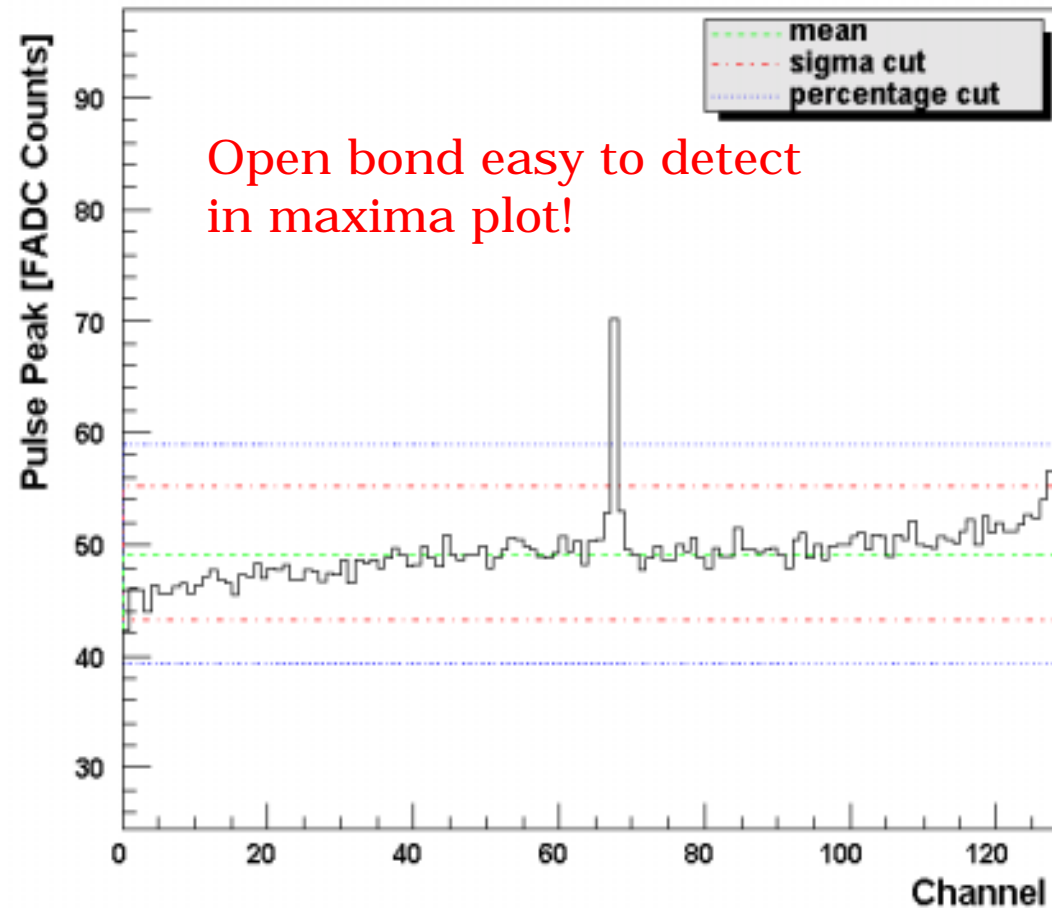
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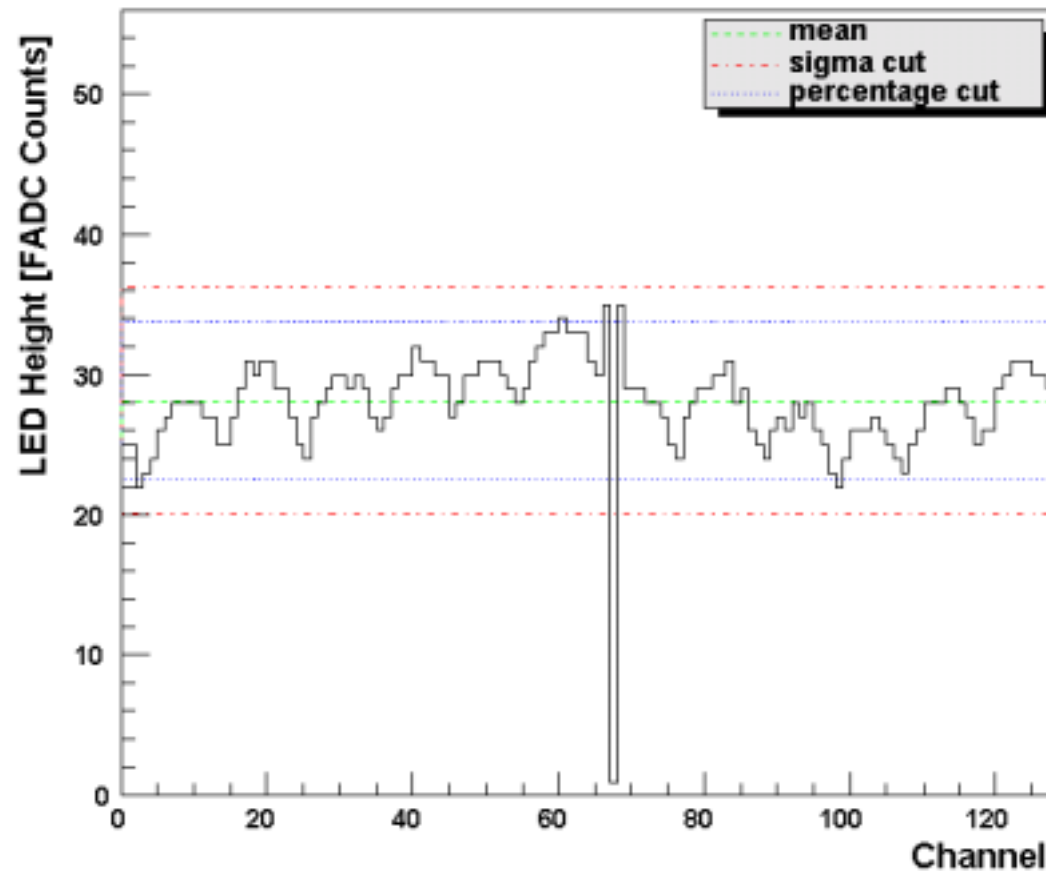
➔ Taking a 100 ns scan around the maximum (dec) should be sufficient!





# Open Bonds III

- LED Test: Of course no signal !
- But which bond (PA-Sen, Sen-Sen) is missing ?  
(if interesting: LED tests on both sensors needed)







# Shorts



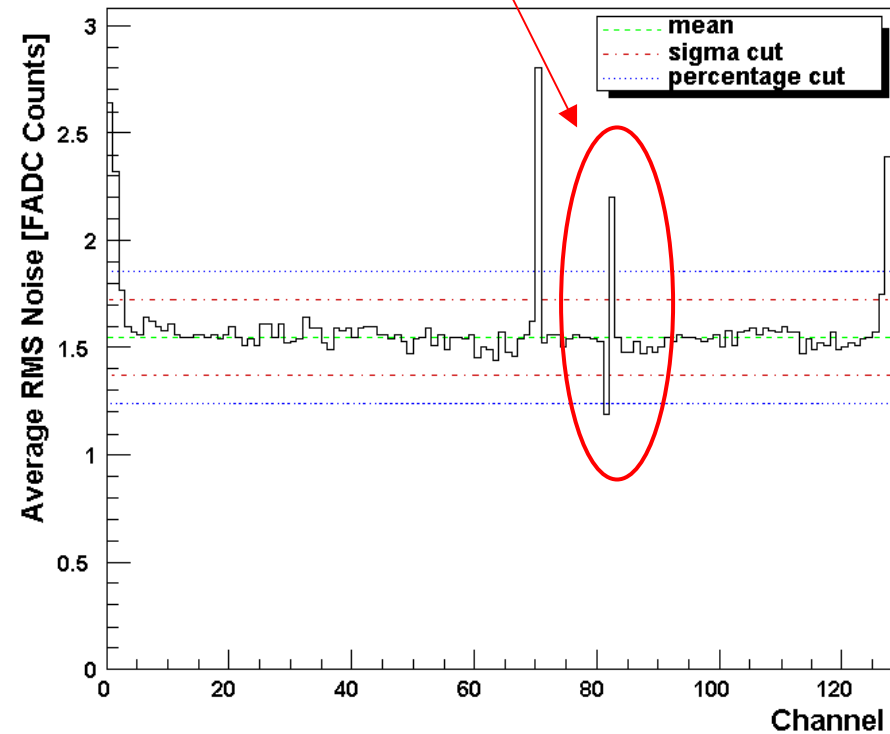
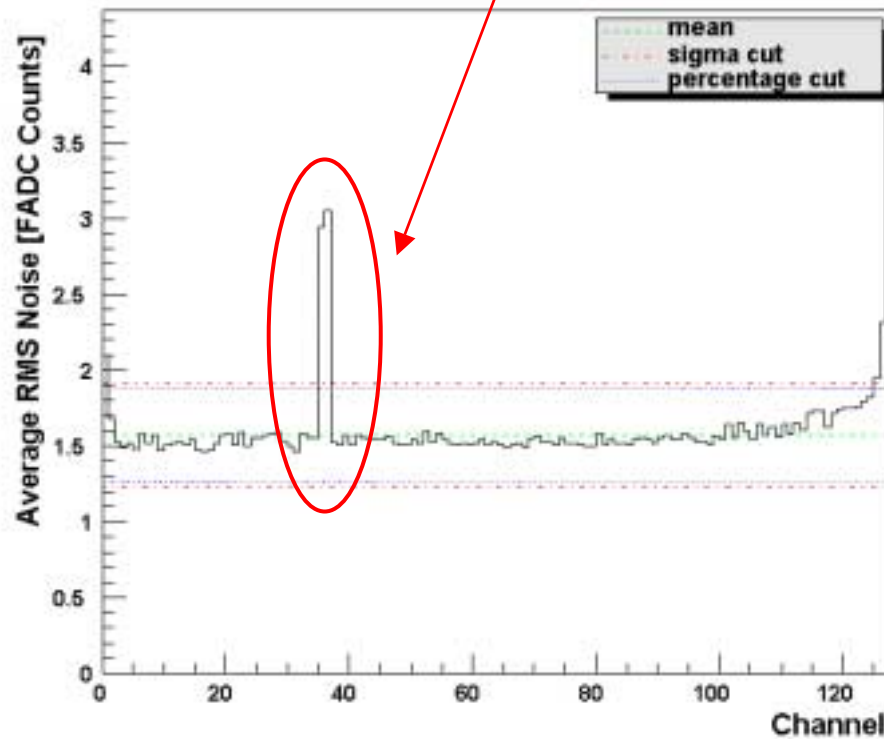
# Shorts I

• Noise:

Higher noise of a **pair** of two neighbouring strips:

or

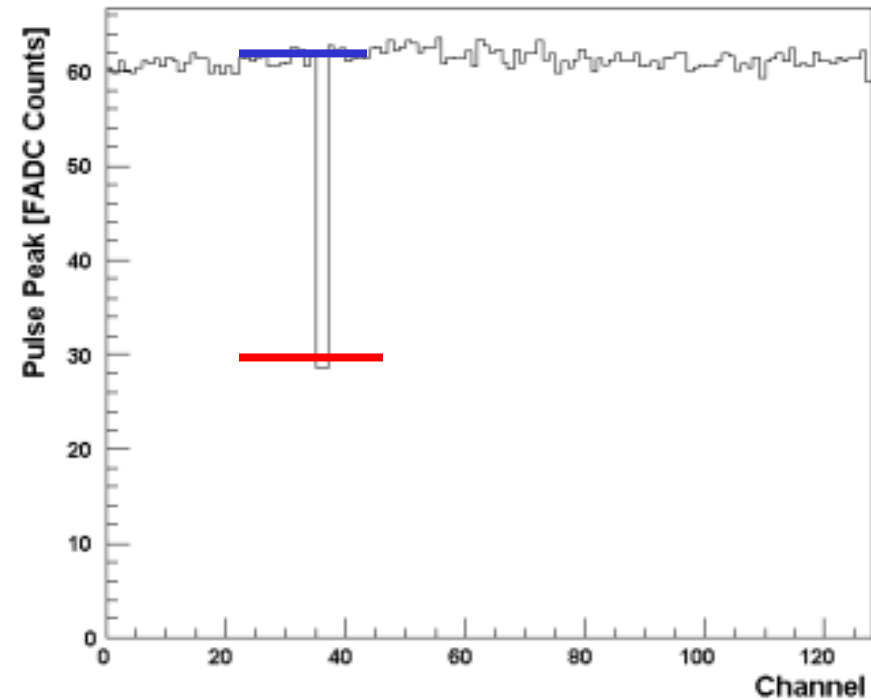
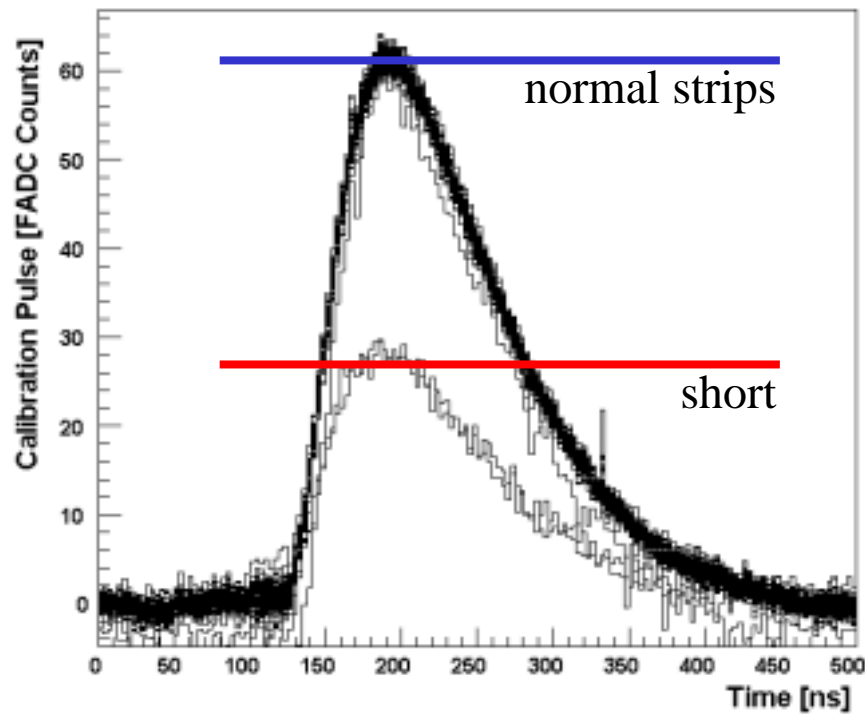
**pair** of strips with higher and lower noise:





# Shorts II

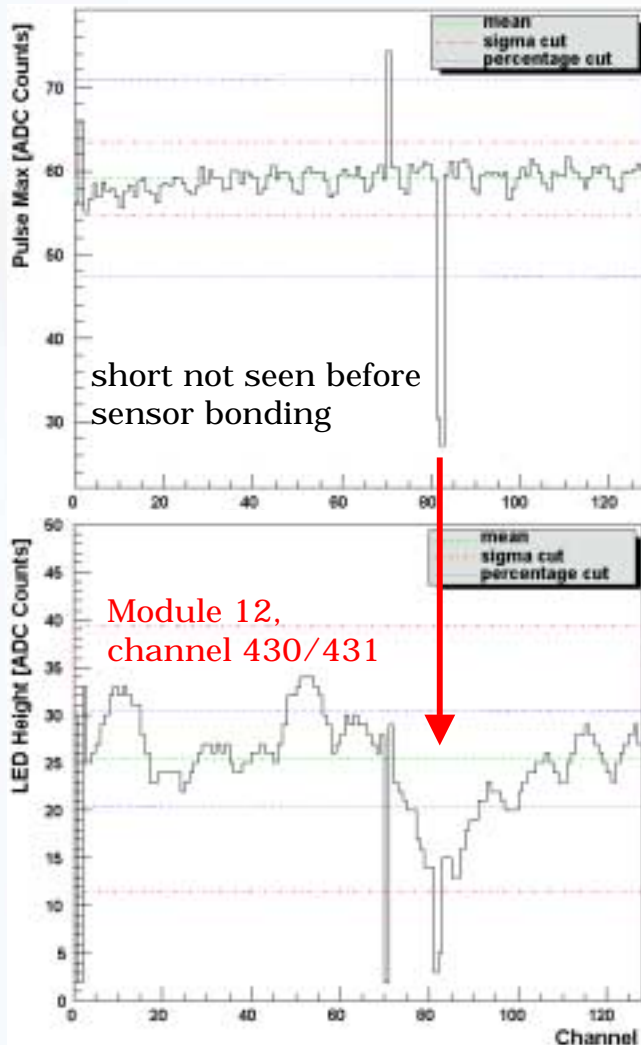
- Pulse Shape: Half the maximum of a “normal strip”





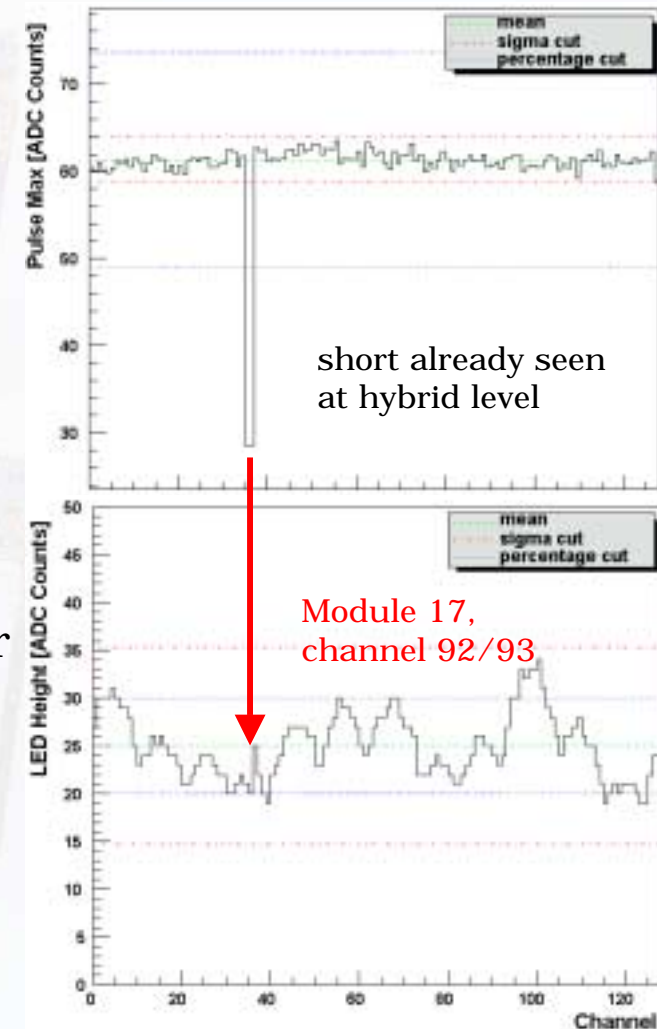
# Shorts III

- Shorts do not have a certain significance in LED tests



same behaviour in pulshape

different behaviour in LED test



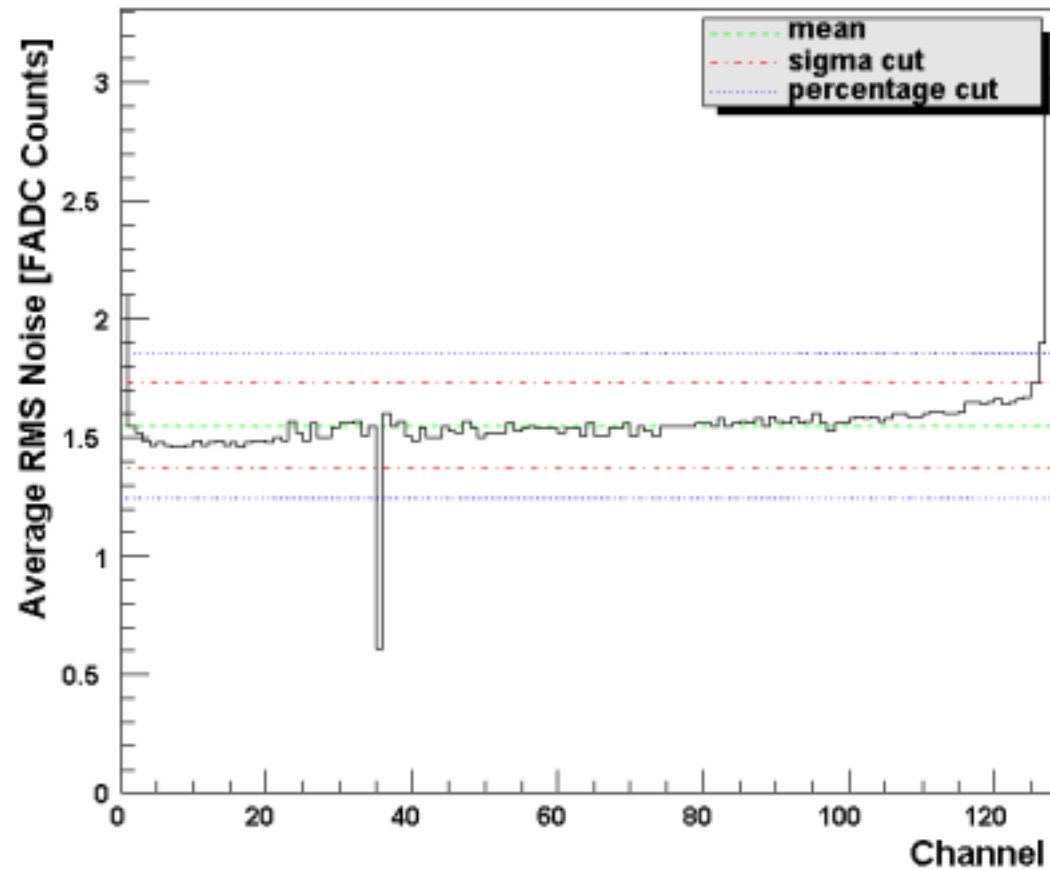


# Pinholes



# Pinholes I

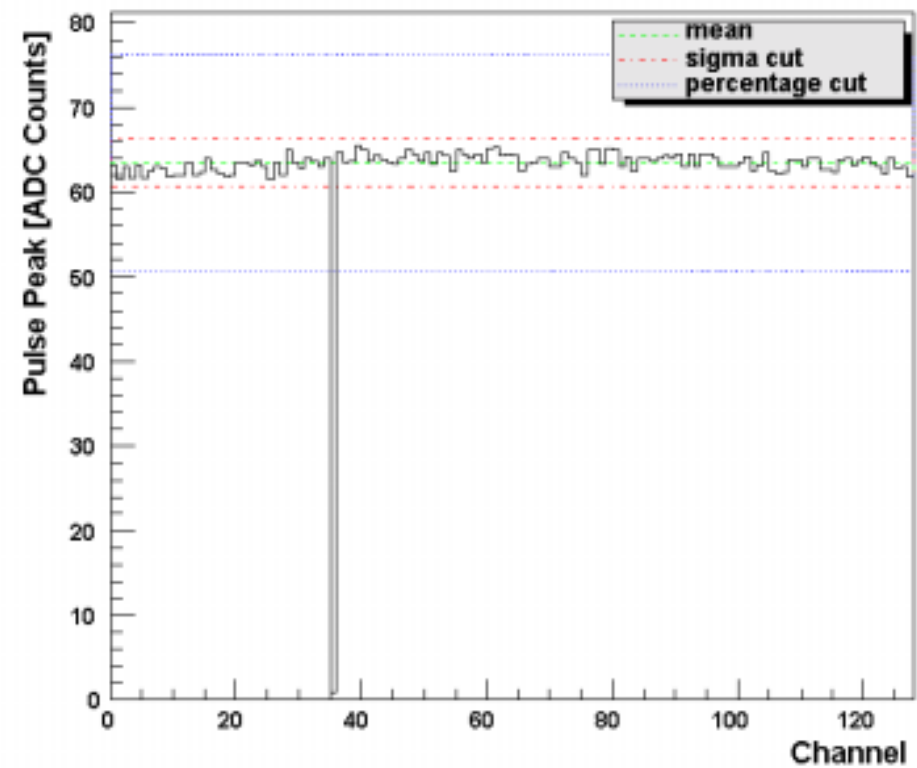
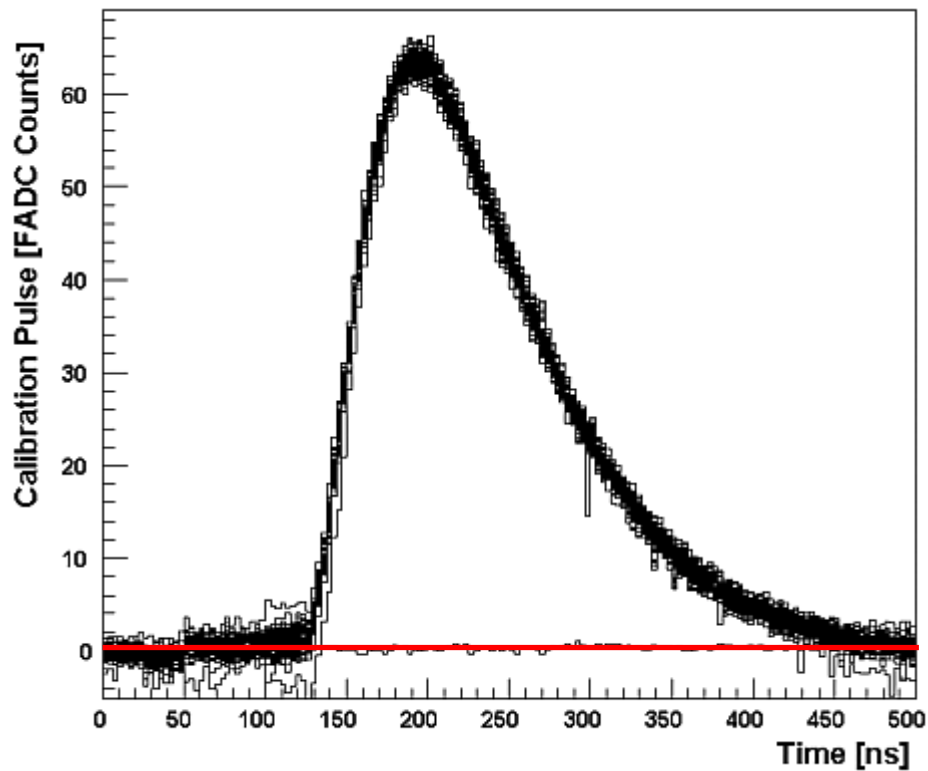
- Noise: Lower noise





# Pinholes II

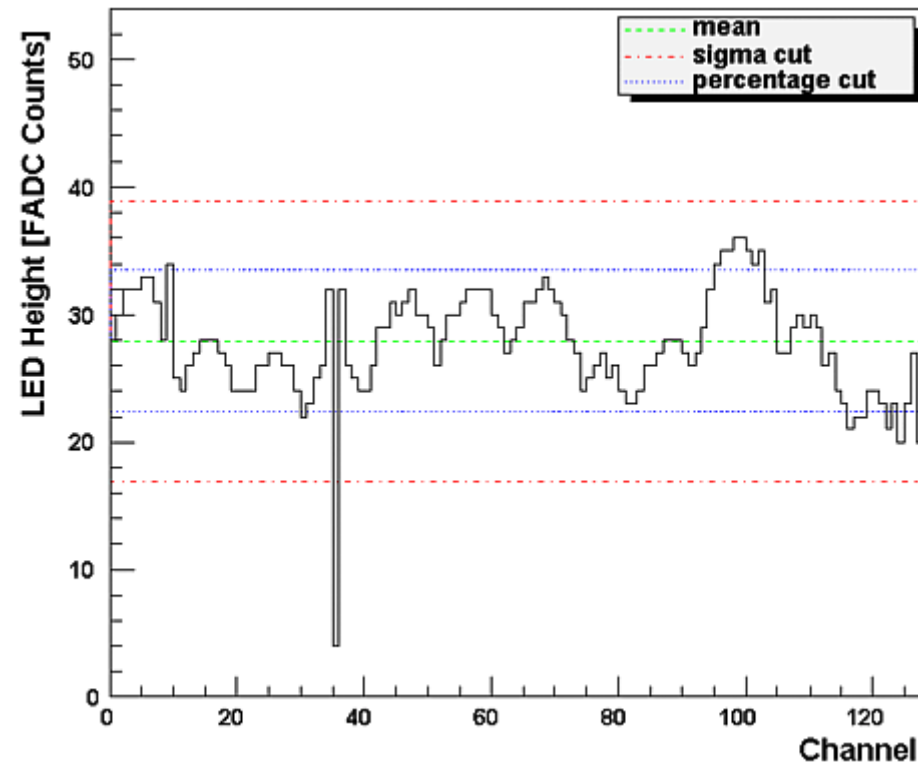
- Pulse Shape: Low Signal resp. no signal (depending on pinhole resistance)





# Pinholes III

- LED Test: Lower Signal

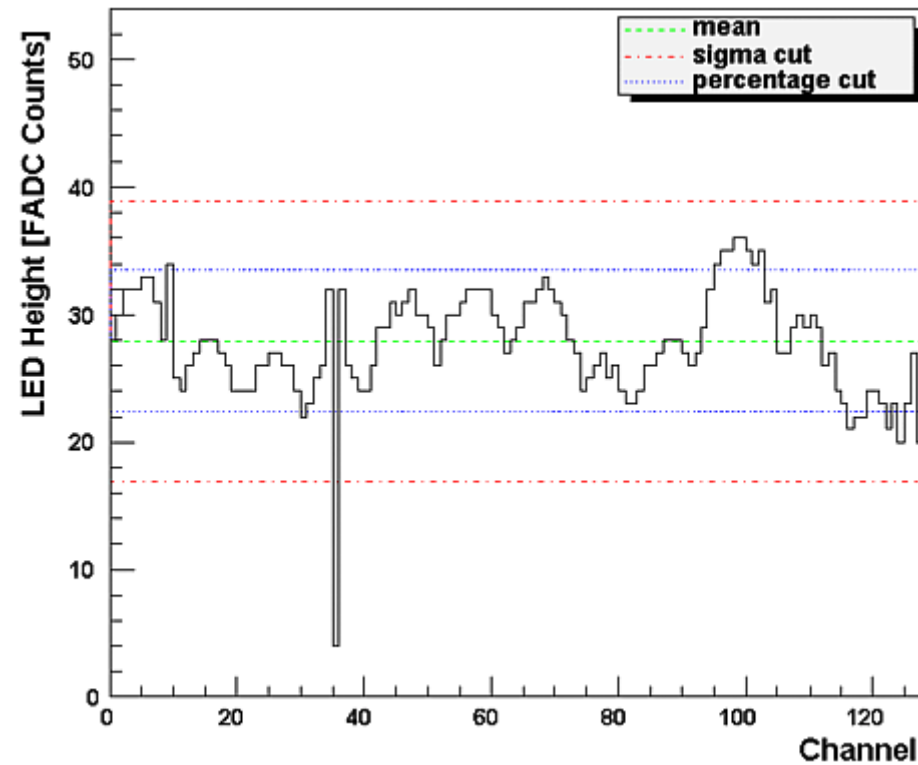






# Pinholes III

- LED Test: Lower Signal





# Defect statistics



• Tabularly summary (  pinhole,  faulty bond,  short ):

Module	Channel	Noise		Pulse Shape				LED Test		Visual Inspection	Description Karlsruhe
		higher	lower	rise time		maximum		signal			
				shorter	longer	higher	lower	higher	lower		
7	-	-	-	-	-	-	-	-	-	-	(Vienna)
12	511	x		x		x			x	missing bond	} lost in cooling tests
	442	x		x		x			x	open bond	
	431		x	x			1/2		x	-	
	430	x		x			1/2		x	-	
	375	x		x		x			x	open bond	
	371	x		x		x			x	open bond	
	346	x		x		x			x	open bond	
	344	x		x		x			x	open bond	
209		x			?		?	x		pinhole	
13	-	-	-	-	-	-	-	-	-	-	(Vienna)
17	443	x		x			1/2		-	-	short on hybrid
	442	x		x			1/2		-	-	short on hybrid
	93	x		x			1/2		-	-	short on hybrid
	92	x		x			1/2		-	-	short on hybrid
20 (PSI)	6	x		x		x			x	open bond	
22	318	x		x		x			x	missing bond	missing bond
23 (PSI)	412	x		x		x			x	?	} artificially bonded
	350		x		-		0		x	bonded pinhole	
	330		x		-		0		x	bonded pinhole	
	310		x		-		0		x	bonded pinhole	
	290	x		x			1/2		x	bonded short	
	289		x		x		1/2		x	bonded short	
	270		x		x		1/2		x	bonded short	
	269	x		x			1/2		x	bonded short	
26	480	x		x		x			x	missing bond	
27	248	x		x		x			x	missing bond	pinhole (unbonded)
	93		x		-		0		x		pinhole
29	189	x		x		x			x	missing bond	
	7		x		-		0		x		pinhole
48	9	x		x		x			x	missing bond	pinhole (unbonded)
56 (PSI)	486	x		x		x			x	open bond	
	307	x		x		x			x	open bond	

12 faulty bonds, 3 shorts, 5 pinholes in total out of 6144 channels: < 0.4 %



# Measurements with cosmics



# Measurements with cosmics

- Our cosmic test station:

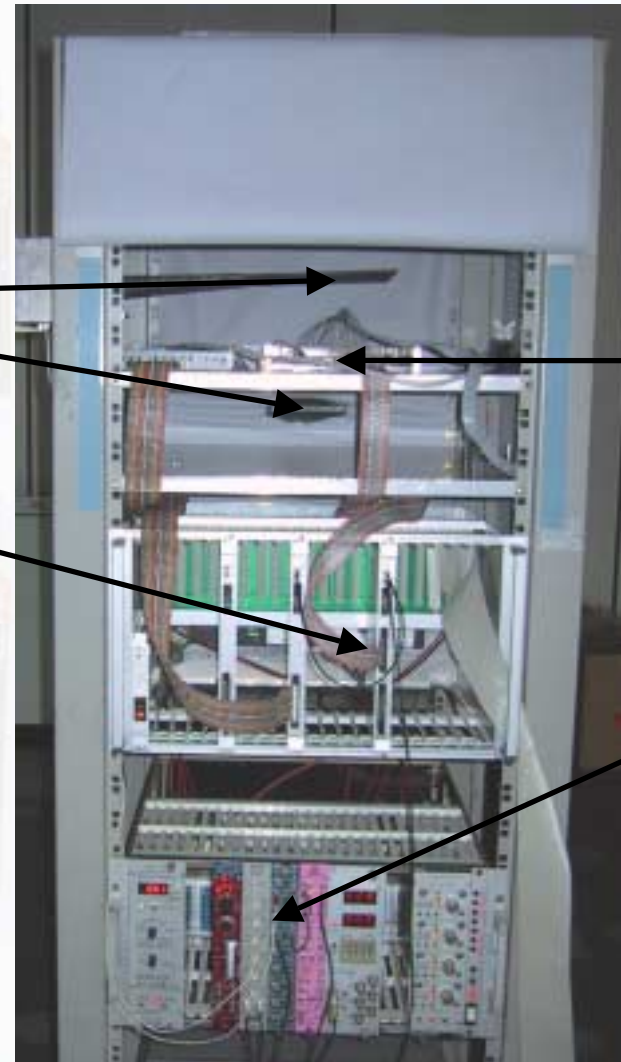
**szintillators**

**ARC-Board**

- Measurements:

**How do pinholes and shorts “react“ on MIPs ?**

*Calibration of ARC Readout, ARCS stability test, signal to noise*



**module 23**

**electronics**



# Measurements with cosmics

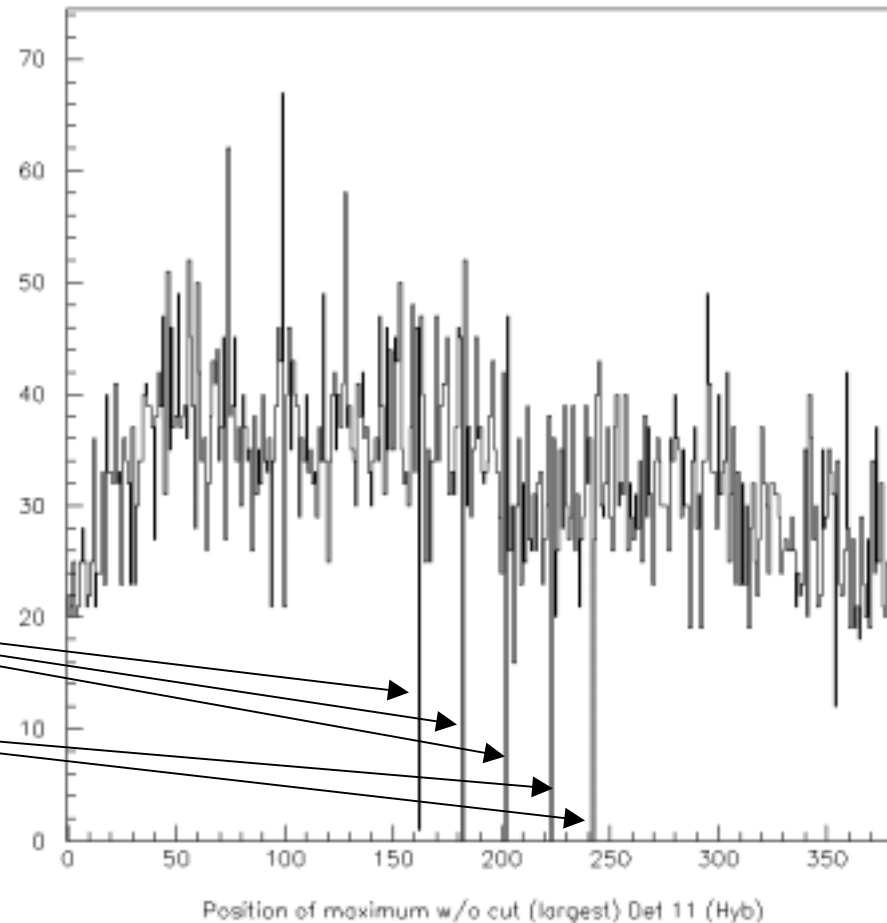
- Module 23 with **2 bonded shorts** and **3 bonded “pinholes”**

- Obvious in a maxima plot:

**Shorts and pinholes are completely „blind“ for MIP particles !**

**Pinholes**

**Shorts**





# Measurements with cosmics

- peak mode,  $V_{\text{depl}} : 100 \text{ V}$

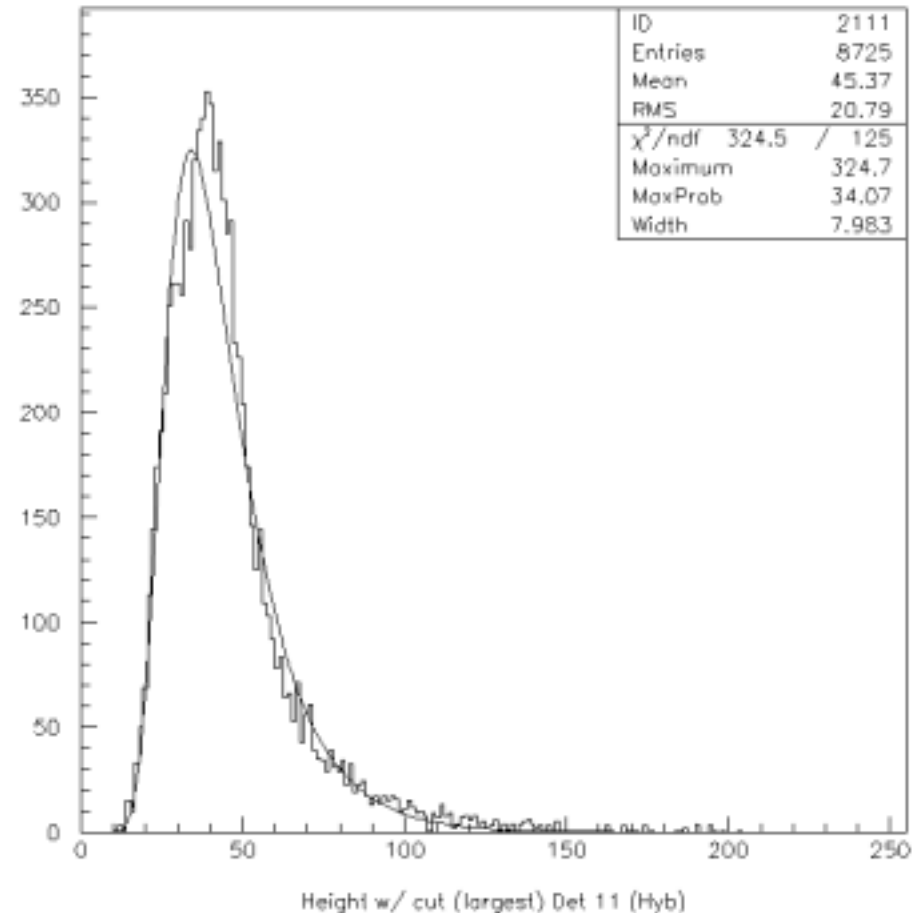
- 3 parameter Landau:

MaxProb: **34 ADC counts**  
(peak mode)

1 MIP  $\sim$  35000 electrons  
(500  $\mu\text{m}$  silicon)

Therefore in ARCS:

**1 ADC  $\sim$  1000 e-**  
(peak mode)





# Measurements with cosmics

- peak mode,  $V_{\text{depl}} : 100 \text{ V}$

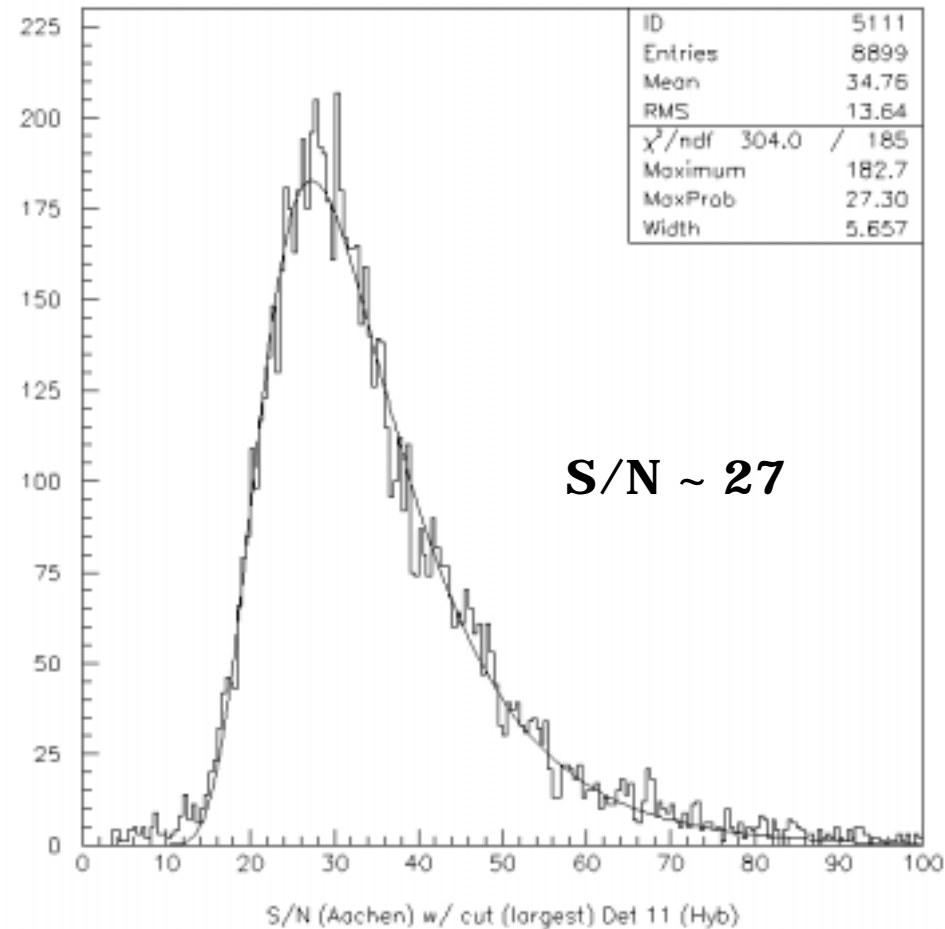
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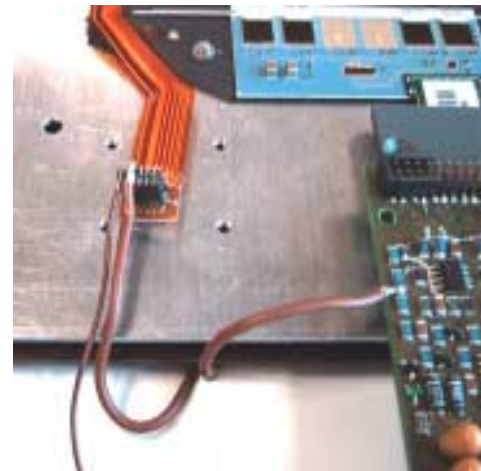
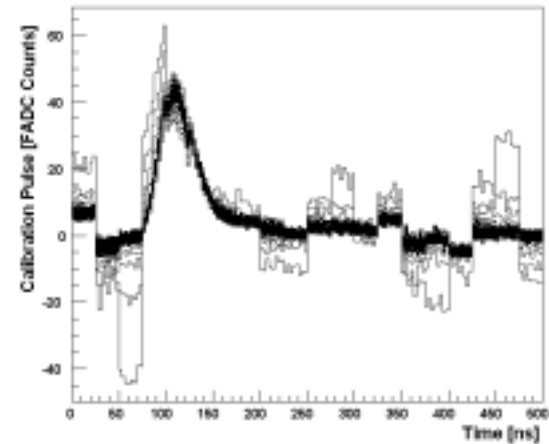
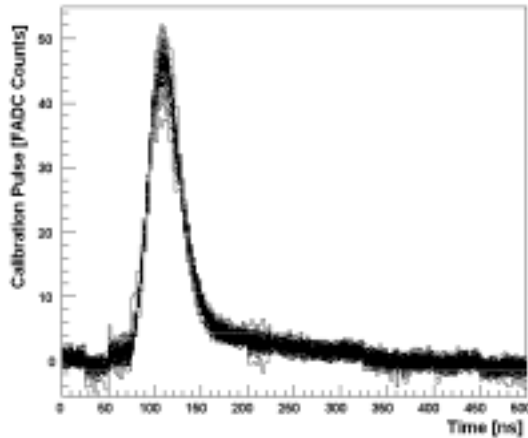
# What we have learned...

- **Faulty Bonds** are easy to detect in all tests, due to higher noise, higher pulse shape maxima, shorter rise time, lower light response. Seen in visual inspection
  - **Shorts** always have conspicuous noise on neighbouring strips, half maximum height in pulse shape, shorter rise time
  - **Pinholes** can be characterized by lower noise, low pulse shape maxima, lower light response (one behaved differently !)
- (**BUT:** An faulty APV channel has the same characteristics, so:  
For pinholes, light tests with high leakage currents a la Karlsruhe could help...)
- The **calibration pulses** are a **powerful tool** for module defect diagnostics (LED/Laser redundant !?)
  - **Same grounding point** essential for comparable data !



# Different Grounding:

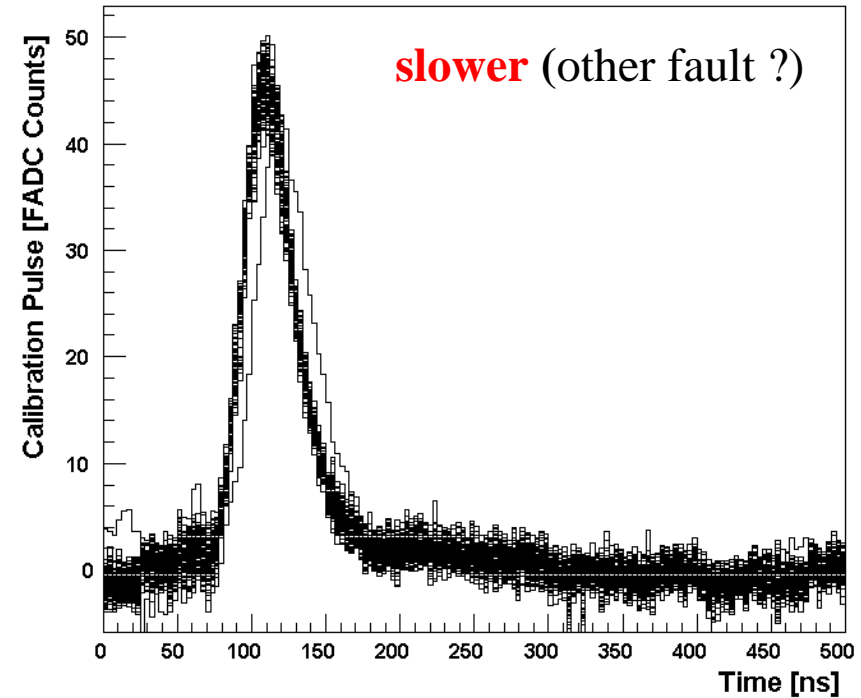
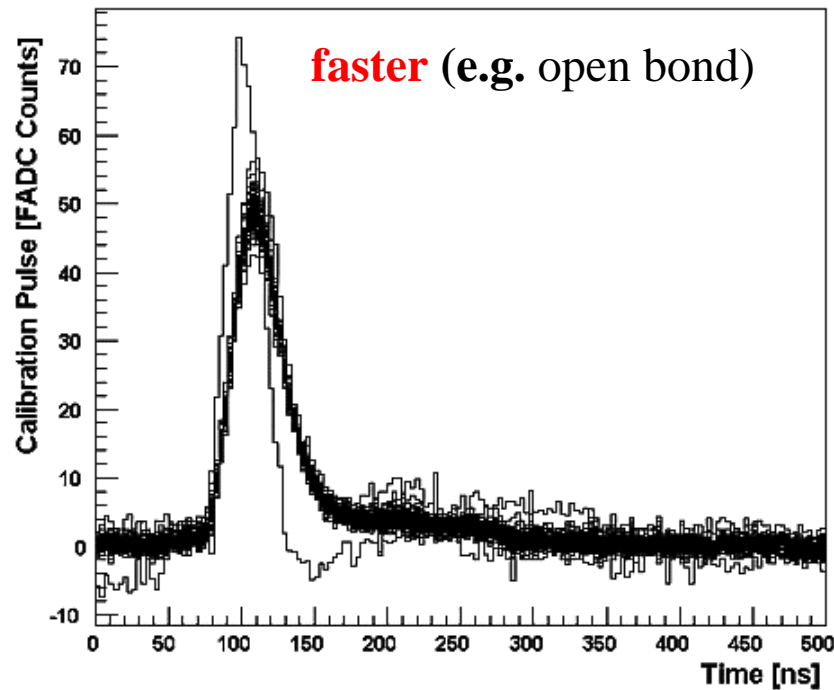
- A “bad grounding” can cause strange effects (e.g. pulse shape):





# Different rise time

- The rising/peak time of the calibration pulse can be another indicator for a fault:



Has to be implemented in ARCS...



# Outlook

- ARCS 5 is ready for all tests (duration ca. 15 minutes per module), except rise/peak time measurements
- We are currently working on the automation routine
- Database connection has to be implemented !!!
- Suggestions are welcome...